Single Ge Quantum Well via a Hybrid Combination of MBE/CVD Growth

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SiGe/Ge/SiGe heterostructures system with Germanium (Ge) as its quantum well (QW) is becoming attractive and a strong candidate for semiconductor spin-qubits applications. This is mainly due to its net-zero nuclear spin for isotopically purified Ge [1]. Furthermore, due to its higher mobility compared to silicon and higher splitting between the heavy-hole (hh) and lighthole (lh) states in the valence band, heavy-hole spins can be manipulated relatively better compared to Si [2]. In this work, we report the fabrication of Si_{1-x}Ge_x /Ge/ Si_{1-x}Ge_x heterostructures for qubits via a hybrid molecular beam epitaxy (MBE)/chemical vapour deposition (CVD) growth. A thick relaxed Si_{0.2}Ge_{0.8} directly grown or a thick Ge virtual substrate (VS) on Si (100)-oriented substrate are realised by CVD. The Si_{1-x}Ge_x /Ge/ Si_{1-x}Ge_x heterostructures are grown

Si _{1-x} Ge, 23 nm Ge QW	¢
Si _{1-x} Ge,	(
Ge virtual substrate	
	100 nm

Fig.1 Cross-section Si_{1-x}Ge_x/Ge/Si_{1-x}Ge_x heterostructure grown via MBE using CVD grown Ge VS/Si (100) substrate. Using HA-BSE SEM mode white contrast corresponds Ge QW and Ge VS while darker contrast corresponds Si_{1-x}Ge_x barrier.

by MBE. The samples are characterized via atomic force microscopy (AFM), selective high-angle backscattered electrons (HA-BSE) scanning electron microscopy (SEM) and Raman spectroscopy.

References

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- 2. N. W. Hendrickx, et al., Nat. Comm. 9, 2835 (2018).